



AMENDMENTS TO THE CLAIMS

1. (currently amended) An X-ray diffractometer, comprising:
a sample stage for mounting a sample, the sample stage being rotatable about an axis;
a double pinhole collimator for directing X-ray radiation to a sample on the sample stage;
a detector for detecting X-rays diffracted by the sample; and
an analyser crystal arranged between the sample stage and the detector to direct X-rays diffracted by the sample onto the detector,
wherein the analyser crystal and detector are rotatable as a unit about an axis that is coaxial with the axis of rotation of the sample stage.
2. (currently amended) An X-ray diffractometer according to claim 1, wherein the size of the pinhole of the double pinhole collimator nearest the sample stage is adjustable for providing an X-ray spot on the sample of variable size.
3. (currently amended) An X-ray diffractometer according to claim 1, wherein a slit is arranged between the sample stage and the detector.
4. (currently amended) An X-ray diffractometer according to claim 3, wherein the slit is arranged in front of the detector.

5. (currently amended) An X-ray diffractometer according to claim 1, and further comprising a drive for rotating the sample stage and the detector and analyser crystal with a ratio of rotation angles of substantially 1:2.